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| Notice of References Cited | Application/Control No. 09/845,655 | Applicant(s)/Patent Under Reexamination AYALA ET AL. | |
| | Examiner Elizabeth Keaney | Art Unit 2882 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| | A | US-6,195,196 | 02-2001 | Kimura et al. | 359/295 |
| | B | US-5,838,100 | 11-1998 | Jansma, Jon Bennett | 313/485 |
| | C | US-6,469,322 | 10-2002 | Srivastava et al. | 257/89 |
| | D | US-6,340,824 | 01-2002 | Komoto et al. | 257/99 |
| | E | US-6,686,676 | 02-2004 | McNulty et al. | 313/112 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|--------|----------------|
| | N | JP 11-145519 | 05-1999 | Japan | Komoto | H01L 33/00 |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | English translation of JP 11-145519 |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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